

Notice of References Cited	Application/Control No. 10/079,800		Applicant(s)/Patent Under Reexamination AKUNE ET AL.	
	Examiner Chat C. Do		Art Unit 2124	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,541,866	07-1996	Sato et al.	708/323
	C	US-5,903,857	05-1999	Behrens et al.	708/300
	D	US-5,892,694	04-1999	Ott, Stefan	708/313
	E	US-5,786,778	07-1998	Adams et al.	708/313
	F	US-5,212,659	05-1993	Scott et al.	708/313
	G	US-6,255,975	07-2001	Swanson, Eric John	341/143
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Adrian et al., A two-path bandpass delta-sum modulator for digital IF extraction at 20 MHz, December 1997, IEEE Journal of solid-state circuits, Vol. 32, No. 12, pages 1920-1934.			
	V	Krzysztof et al., Effects of noise dither signals on differential linearity and effective resolution of sigma-delta A/C converters in measuring applications, May 1998, IEEE Instrumentation and Measurement Technology Conference, pages 1229-1232.			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.